

DTQ3D306

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N- and P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
	V _{DS} (V)	R_{DS(on)} (Ω)	I _D (A) ^a	Q _g (Тур.)		
N-Channel	30	0.015 at V $_{\rm GS}$ = 10 V	18	12.5		
		$0.020 \text{at V}_{GS} = 4.5 \text{V}$	14	12.0		
P-Channel	- 30	0.039 at V_{GS} = - 10 V	- 12	5		
		0.060 at V _{GS} = - 4.5 V	- 8	5		

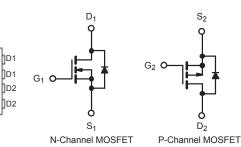
FEATURES

- DT-Trench Power MOSFET
- 100% Rg and UIS Tested

APPLICATIONS

- Networking DC-DC Power System
- Load Switch







ABSOLUTE MAXIMUM RATING	S T _A = 25 °C, unle	ess otherwis	se noted		
Parameter	Symbol	N-Channel	P-Channel	Unit	
Drain-Source Voltage	V _{DS}	30	- 30	v	
Gate-Source Voltage		V _{GS}	± 20		l v
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C		18	-12	
	T _C = 70 °C		15	- 8	
	T _A = 25 °C	^{'D}	12 ^{b, c}	- 8.3 ^{b, c}	
	T _A = 70 °C		9.4 ^{b, c}	- 6.5 ^{b, c}	
Pulsed Drain Current		I _{DM}	72	-48	А
Source-Drain Current Diode Current	T _C = 25 °C		15	- 10	
	T _A = 25 °C	- I _S -	8 ^{b, c}	- 5 ^{b, c}	
Pulsed Source-Drain Current		I _{SM}	72	-48	
Single Pulse Avalanche Current		I _{AS}	40	-27	
Single Pulse Avalanche Energy	L = 0 1 mH	E _{AS}	20	-12	mJ
	T _C = 25 °C		12.5	6	
Maximum Power Dissipation	T _C = 70 °C	P _D	5	2.9	w
	T _A = 25 °C	ГD	4.3 ^{b, c}	2.0 ^{b, c}	vv
	T _A = 70 °C	1 [2.25 ^{b, c}	1.25 ^{b, c}	7
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to	°C		

THERMAL RESISTANCE RATINGS N-Channel P-Channel Max. Max. Parameter Symbol Тур. Тур. Unit Maximum Junction-to-Ambient^{b, d} $t \leq 10 \ s$ R_{thJA} 54 64 25 30 °C/W Maximum Junction-to-Foot (Drain) Steady State R_{thJF} 70 85 50 60

Notes:

a. Based on T_C = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 120 °C/W.

Parameter	Symbol	Test Conditions		Min.	Typ. ^a	Max.	Unit	
Static						1		
		V _{GS} = 0 V, I _D = 250 μA	N-Ch	30				
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	P-Ch	- 30			V	
V _{DS} Temperature Coefficient		I _D = 250 μA	N-Ch		44		_ _ mV/°C	
	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA	P-Ch		- 42			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	N-Ch		- 5.5			
		I _D = - 250 μA	P-Ch		4.6			
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	N-Ch	1		3	- v	
		V _{DS} = V _{GS} , I _D = - 250 μA	P-Ch	- 1		- 3		
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 20 V	N-Ch			100	- nA	
			P-Ch			- 100		
Zero Gate Voltage Drain Current		V _{DS} = 24 V, V _{GS} = 0 V	N-Ch			1		
		V _{DS} = - 24 V, V _{GS} = 0 V	P-Ch			- 1	μΑ	
	IDSS	V _{DS} = 24 V, V _{GS} = 0 V, T _J = 55 °C	N-Ch			10		
		V _{DS} = - 24 V, V _{GS} = 0 V, T _J = 55 °C	P-Ch			- 10		
On-State Drain Current ^b		V _{DS} = 5 V, V _{GS} = 10 V	N-Ch	72			A	
	I _{D(on)}	V _{DS} = - 5 V, V _{GS} = - 10 V	P-Ch	- 48				
Drain-Source On-State Resistance ^b	R _{DS(on)}	V _{GS} = 10 V, I _D = 10 A	N-Ch		0.015	0.018	Ω	
		V _{GS} = - 10 V, I _D = - 8 A	P-Ch		0.039	0.047		
		V _{GS} = 4.5 V, I _D = 8 A	N-Ch		0.020	0.025		
		V _{GS} = - 4.5 V, I _D = - 5 A	P-Ch		0.060	0.067		
	9 _{fs}	V _{DS} = 15 V, I _D = 10 A	N-Ch		25		+	
Forward Transconductance ^b		V _{DS} = - 15 V, I _D = - 8 A	P-Ch		12		S	
Dynamic ^a			<u> </u>		1	1	I	
			N-Ch		650			
Input Capacitance	C _{iss}	N-Channel	P-Ch		570		– – pF –	
Output Capacitance	C _{oss}	V_{DS} = 24 V, V_{GS} = 0 V, f = 1 MHz	N-Ch		190			
	C _{OSS}	P-Channel	P-Ch		80			
Reverse Transfer Capacitance	C _{rss}	V_{DS} = - 24 V, V_{GS} = 0 V, f = 1 MHz	N-Ch		95			
			P-Ch		45			
	Qg	V_{DS} = 24 V, V_{GS} = 10 V, I_D = 10 A	N-Ch		12.5	22	1	
Total Gate Charge		$V_{DS} = -24 V, V_{GS} = -10 V, I_D = -8 A$	P-Ch		5	18		
		N-Channel	N-Ch		5.3	9	nC	
	Q _{gs}	$V_{DS} = 24 V, V_{GS} = 4.5 V I_{D} = 8 A$	P-Ch		1.8	3		
Gate-Source Charge			N-Ch		1.4			
	Q _{gd}	P-Channel	P-Ch		0.55		-	
Gate-Drain Charge		V_{DS} = - 24 V, V_{GS} = - 4.5 V, I_D = - 5 A	N-Ch P-Ch		1.9 1.1		-	
		f = 1 MHz	N-Ch	0.5	2.0	4.5		
Gate Resistance	Rg		P-Ch	1.0	3.5	11	Ω	



Parameter	Symbol	Test Conditions		Min.	Typ. ^a	Max.	Unit
Dynamic ^a							
Turn-On Delay Time	t _{d(on)}	N-Channel	N-Ch		7	14	
	a(0.1.)	$V_{DD} = 24 \text{ V}, \text{ R}_{I} = 4 \Omega$	P-Ch		8	17	-
Rise Time	t _r	$I_D \cong 10 \text{ A}, V_{\text{GEN}} = 10 \text{ V}, R_g = 1 \Omega$	N-Ch		10	25	
		-	P-Ch N-Ch		13 15	27 32	
Turn-Off Delay Time	t _{d(off)}	P-Channel	P-Ch		33	65	
		$V_{DD} = -24 \text{ V}, \text{ R}_{L} = 4 \Omega$ $\text{I}_{D} \cong -8 \text{ A}, \text{ V}_{\text{GEN}} = -10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$	N-Ch		9	22	
Fall Time	t _f	10 = 0.73, 0 GEN = 10.03, 100 GEN = 1.22	P-Ch		9	23	
			N-Ch		16	30	ns
Turn-On Delay Time	t _{d(on)}	N-Channel	P-Ch		47	80	-
Rise Time		$V_{DD} = 24 V, R_L = 4 \Omega$	N-Ch		19	30	
	t _r	$\text{I}_\text{D}\cong\text{8}$ A, V_GEN = 4.5 V, R_g = 1 Ω	P-Ch		33	50	
Turn Off Dalay Time	t	P-Channel	N-Ch		16	30	
Turn-Off Delay Time	t _{d(off)}		P-Ch		28	60	
Fall Time	t _f	$I_D \cong -5 \text{ A}, \text{ V}_{\text{GEN}}$ = - 4.5 V, R_g = 1 Ω	N-Ch		10	20	
			P-Ch		13	25	
Drain-Source Body Diode Characterist	ics						1
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	N-Ch			15	-
Continuous Source-Drain Diode Currer			P-Ch			-10	A
Pulse Diode Forward Current ^a			N-Ch			72	-
		I _S = 1.6 A	P-Ch		0.70	-48	
Body Diode Voltage	V _{SD}		N-Ch		0.78	1.2	V
		I _S = - 1.6 A	P-Ch		- 0.76	- 1.2	
Body Diode Reverse Recovery Time	t _{rr}		N-Ch P-Ch		7	34	ns
Body Diode Reverse Recovery Charge	Q _{rr}	N-Channel	P-Ch N-Ch		5	55 25	
		I_F = 2 A, dl/dt = 100 A/µs, T _J = 25 °C	P-Ch		4 1.5	35	nC
			N-Ch		1.5	00	
Reverse Recovery Fall Time	ta	P-Channel I _F = - 2 A, dl/dt = - 100 A/µs, T _{.1} = 25 °C	P-Ch		17		-
		$F = -2 \Lambda$, u/u(= -100 Λ µs, 1j = 25 C	N-Ch		6		ns
Reverse Recovery Rise Time	t _b		P-Ch		15		1

Notes:

a. Guaranteed by design, not subject to production testing. b. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



2.0

24

V_{GS} = 4.5 V

100

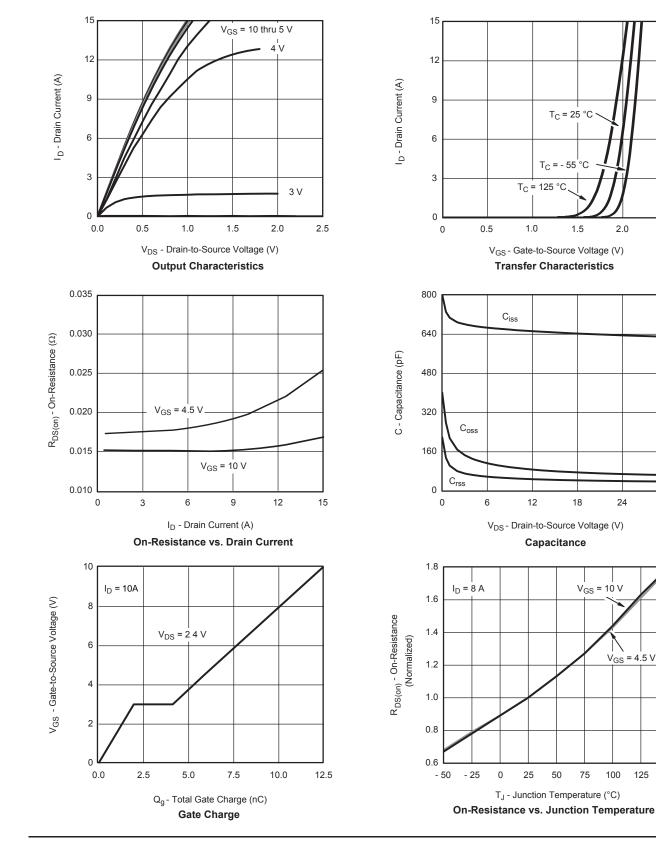
75

125 150

V_{GS} = 10 V

30

2.5



N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



I_D = 10 A

T_A = 125 °C

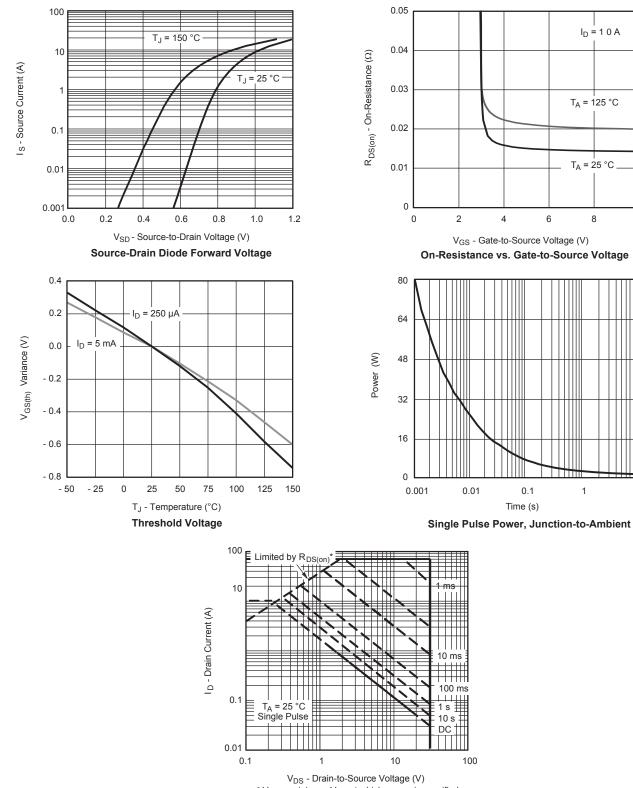
T_A = 25 °C

8

10

10

1

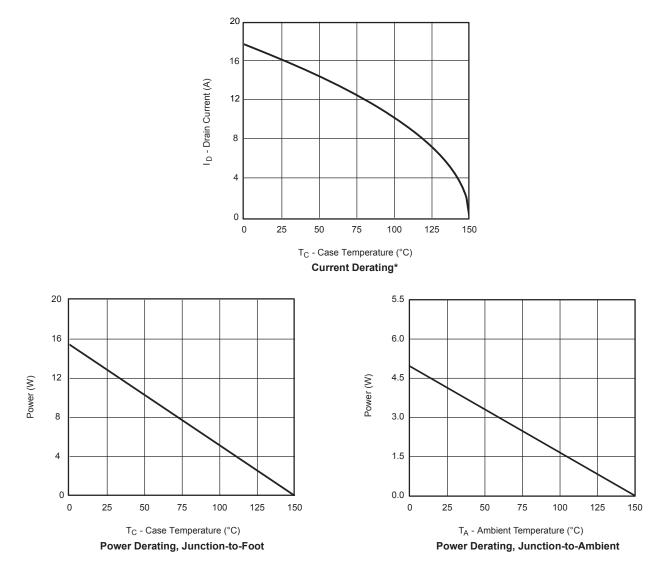


N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

* V_{GS} > minimum V_{GS} at which $r_{DS(on)}$ is specified Safe Operating Area, Junction-to-Ambient

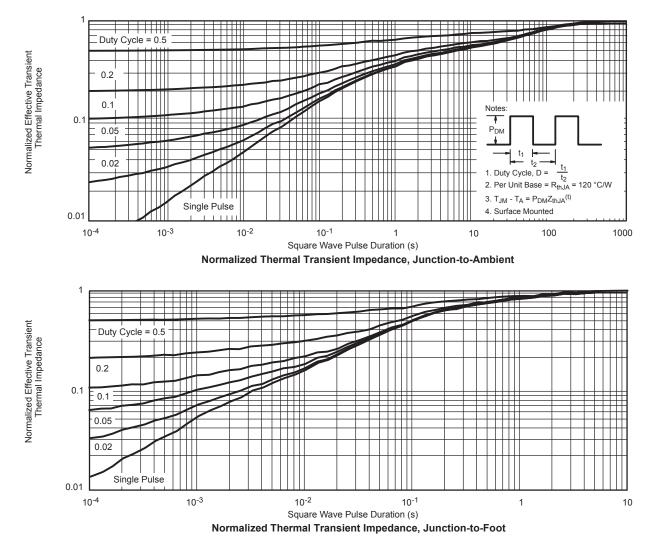


N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



2.0

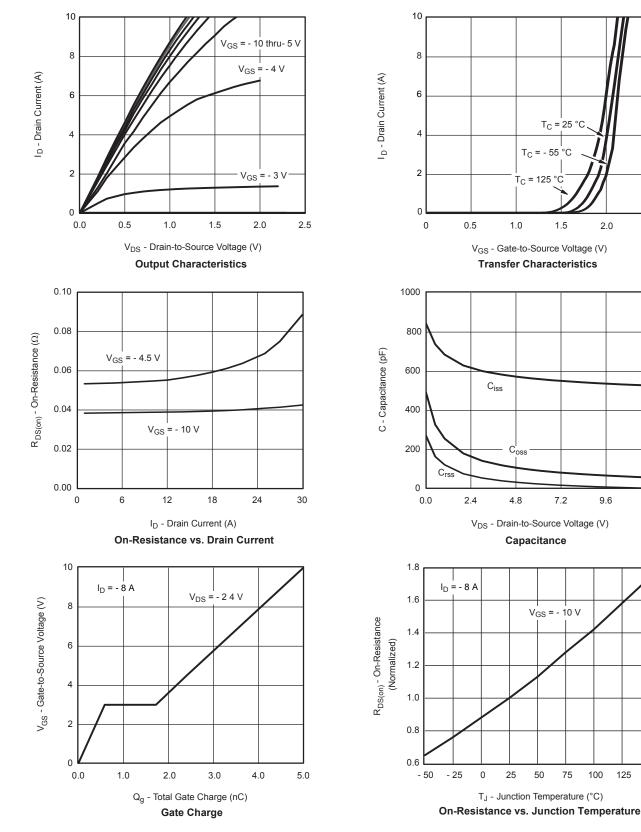
9.6

100

125 150

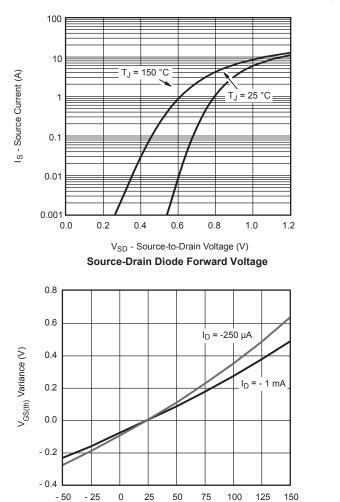
12.0

2.5



P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

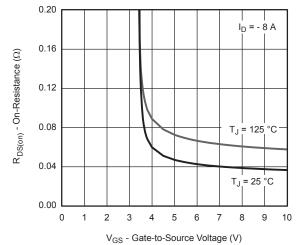




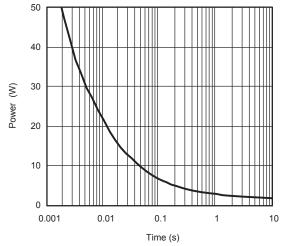
T_J - Temperature (°C)

Threshold Voltage

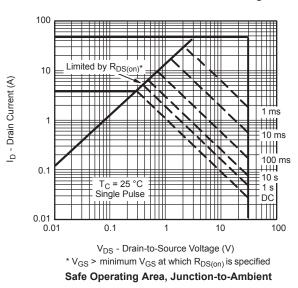
P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



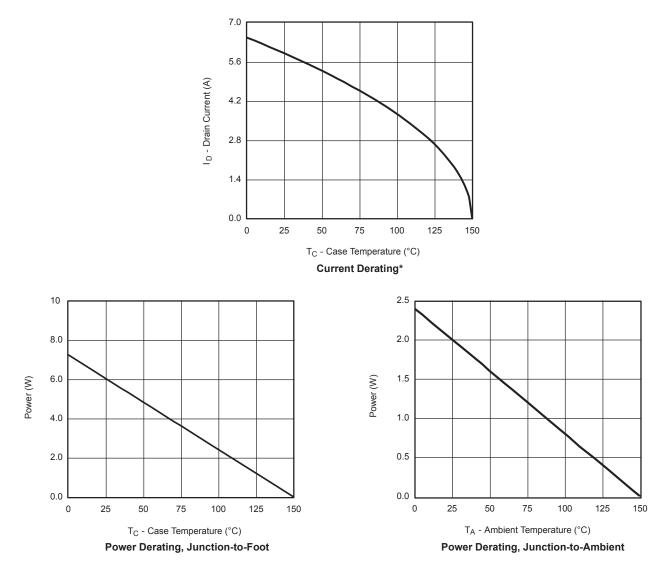
On-Resistance vs. Gate-to-Source Voltage







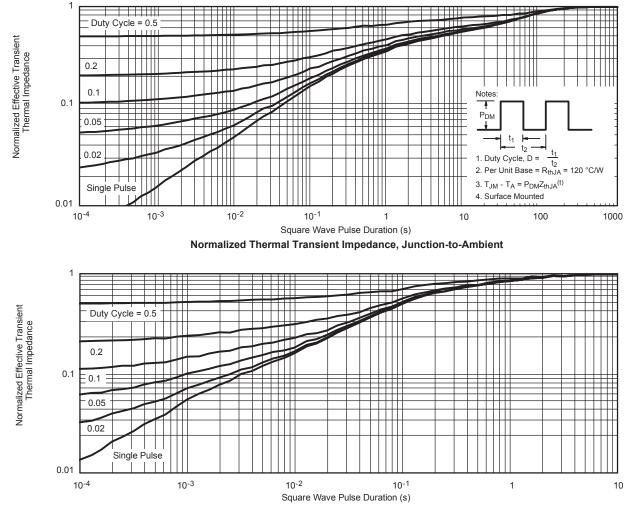




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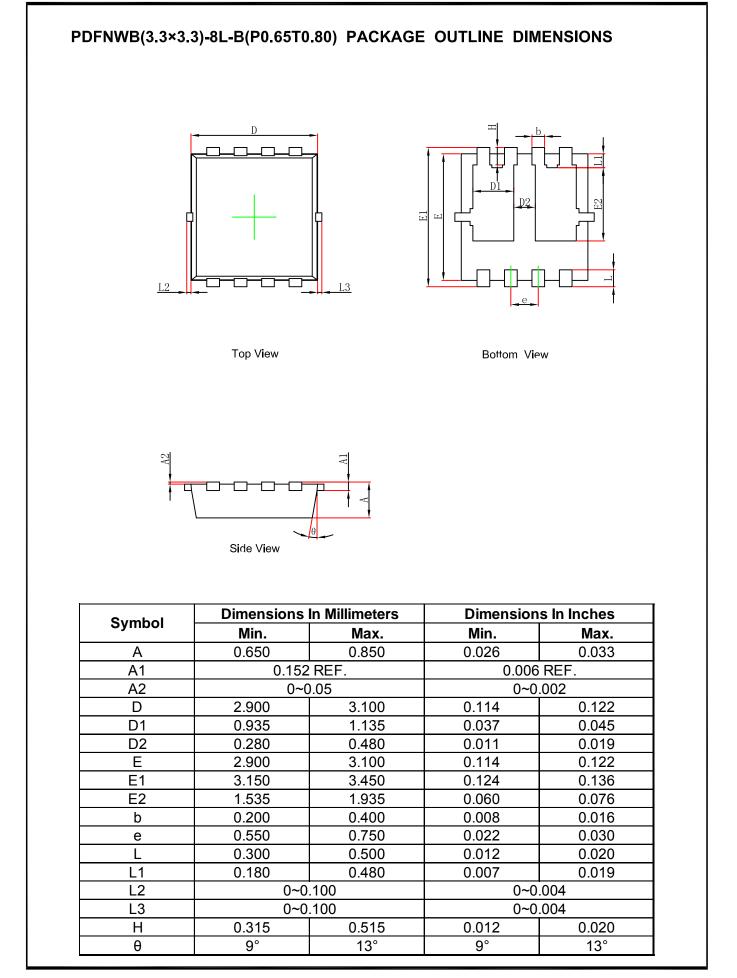


P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Foot



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